

Pulse Profiling for AlGaN/GaN HEMTs Large Signal Characterizations

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Motivations for LSNA Load-Pull Measurements Pulse Profiling

The LSNA

Pulse Profile Mode of LSNA Load-PULL

The Pulsed and Pulse Profiling Measurement Results

Conclusions and Perspectives

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Conclusions and Perspectives



- Key factors in power amplifiers

- Linearity
- Gain
- Power Efficiency

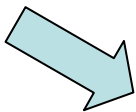
- Tendencies:

- New devices (GaN)
- New designs (Switched amplifiers)
- New requirements (High power, Wideband modulations)

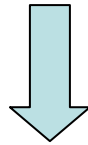
- Designer's nightmares:
 - Memory effects : Thermal effects, Traps
 - Reliability
 - Poor models

- Rescue solutions:
 - Device Measurements
 - Circuit Measurements
 - Comparison with simulation results

- Time Domain Load-Pull setups can measure the drain load line of devices up to very high power



- But... more and more high power devices are used in pulsed mode, or with very high peak to average ratios



- The memory effects are more and more to be accurately considered, in particular the shift of characteristics
- RF designers can take benefits of transient envelope simulators. But once again, such simulations have to be checked with measurements



We will propose a measurement system with the capability to perform pulse profiling of time domain measurements

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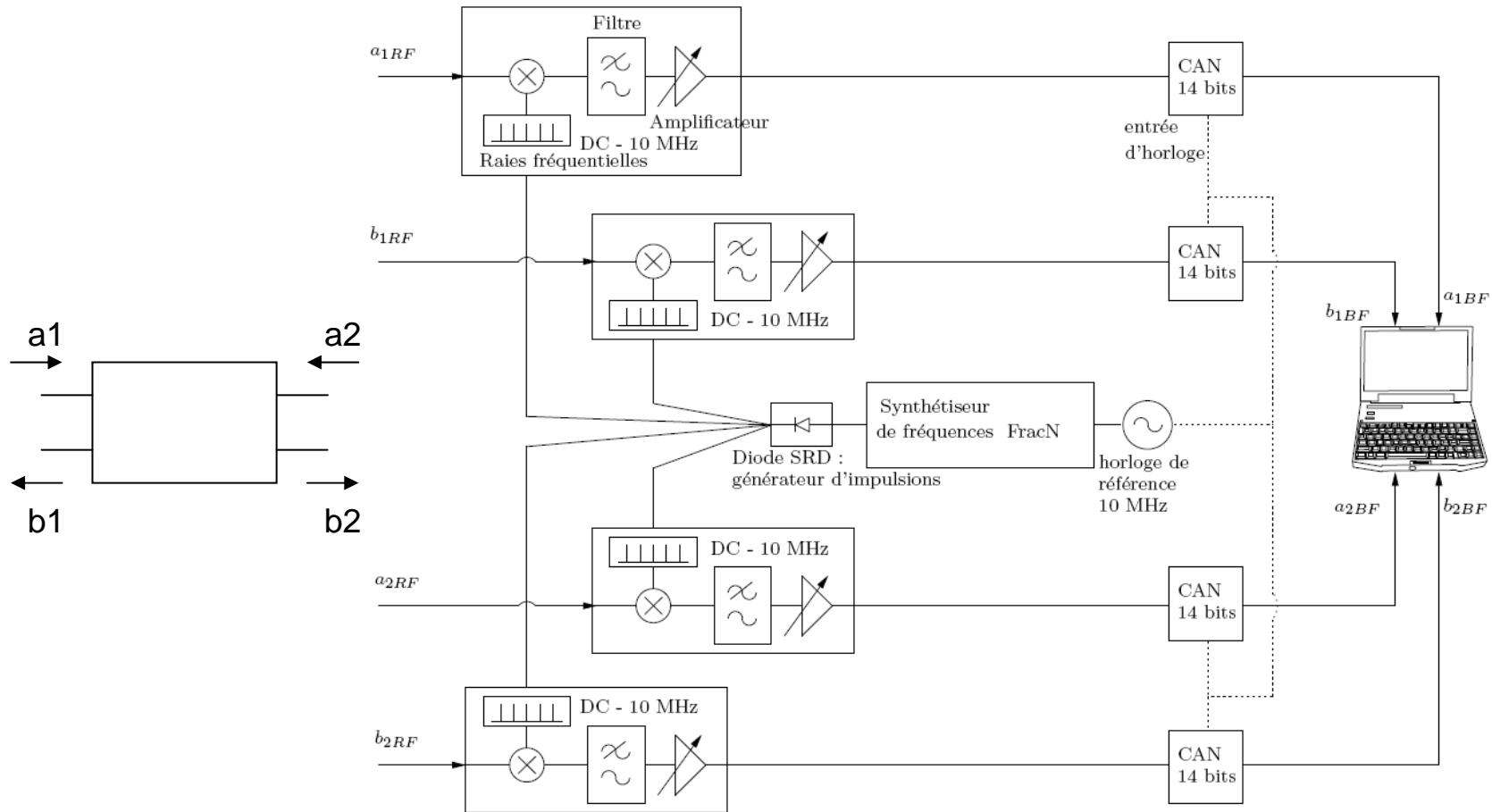
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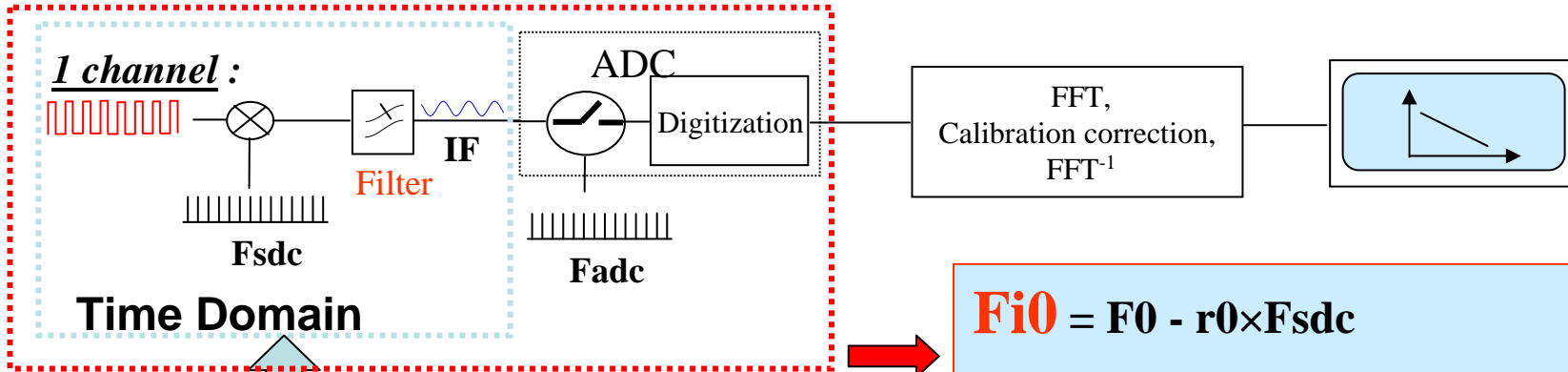
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The LSNA



A 4 paths and 4 samplers system

The LSNA in CW Mode

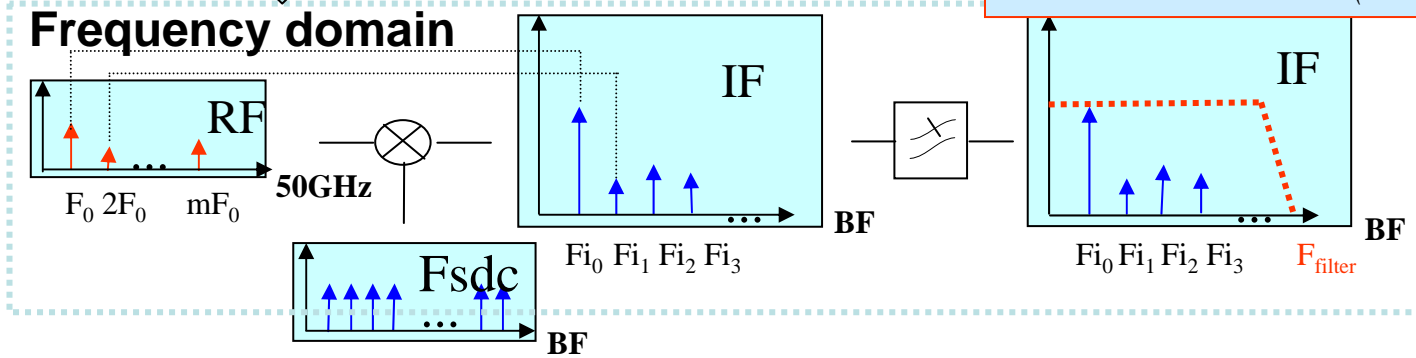


$$F_{i0} = F_0 - r_0 \times F_{sdc}$$

...

$$F_{im} = (m+1) \times F_0 - r_m \times F_{sdc} < F_{\text{filtre}}$$

et $F_{adc} > 2 \times F_{im}$ (Shannon)



All the frequency components of interest are simultaneously available in the IF domain



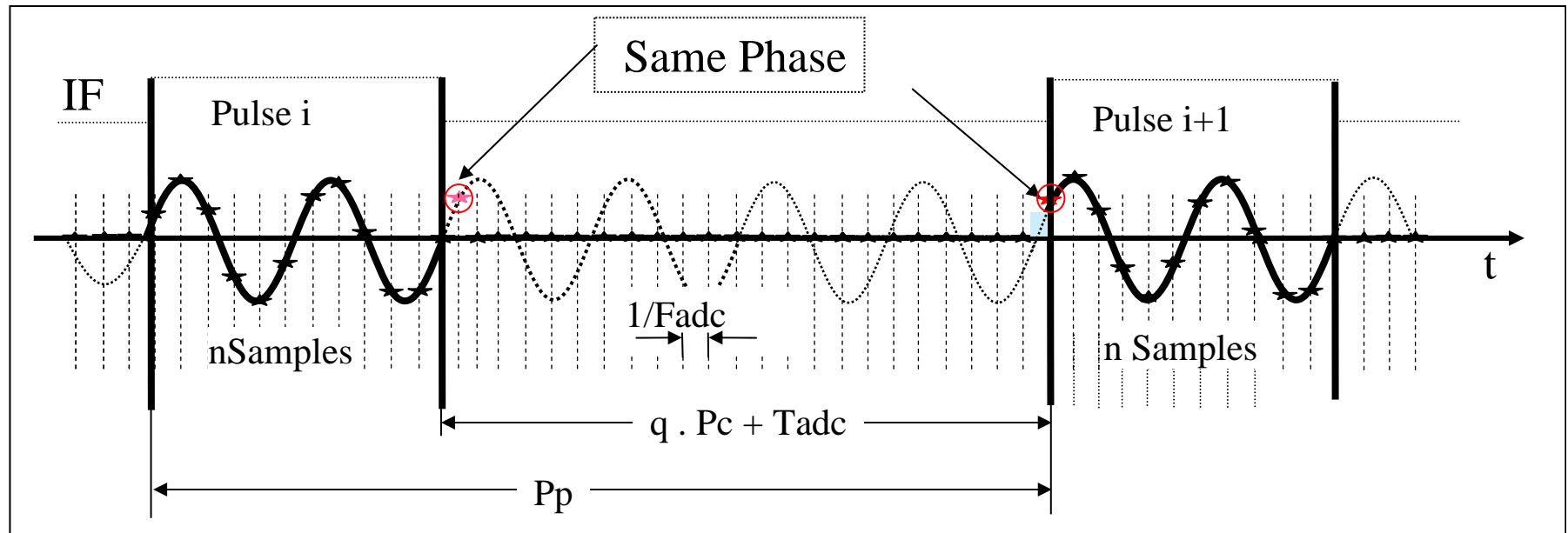
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⇔ Two mathematical relationships:

- a common period between F_0 , F_{sdc} , F_{adc} noted P_c
- a relationship between the common period P_c and the Pulses period (P_p) $\Rightarrow P_p = q \times P_c + (n-1) \times T_{adc} + T_{adc}$

A synchronized pulsed mode without dynamical losses

- The Same conditions for CW mode (F_0, \dots, mF_0):

$$F_{i0} = F_0 - r_0 \times F_{sdc}$$

...

$$F_{im} = (m+1) \times F_0 - r_m \times F_{sdc} < F_{filtre}$$

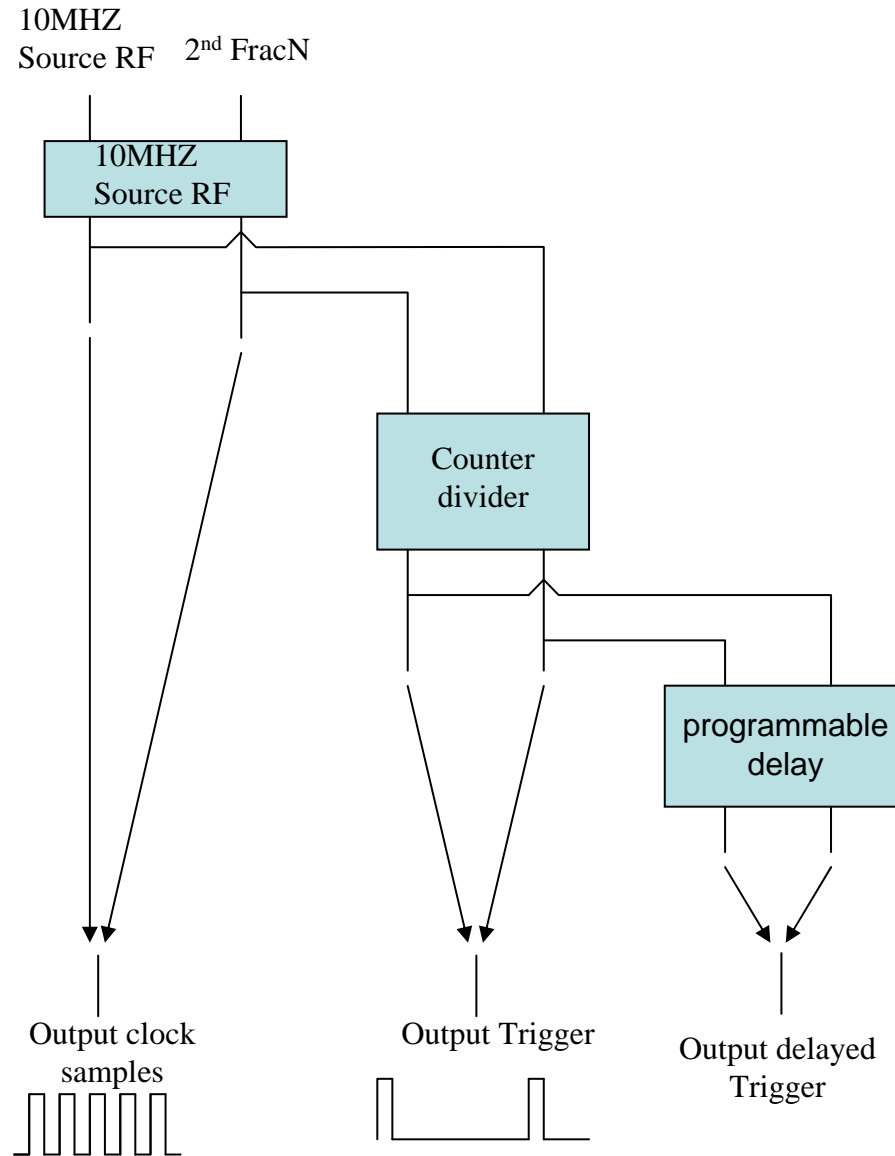
$$F_{adc} > 2 \times F_{im}$$

- Plus : Careful selection for the Pulse Period.
 Locking the phase of all signals on the reference signal (10 MHz).

Development of a specific program

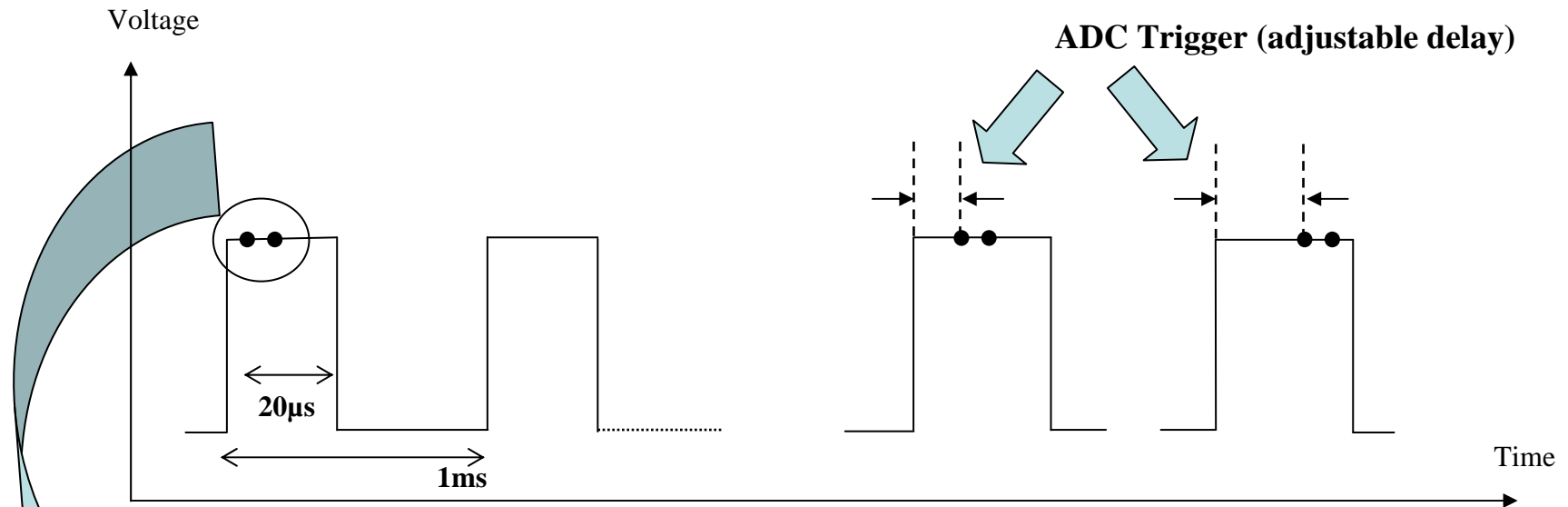
- Input : F_0, n, P_{pa} (arbitrary Pulse period)
- Output : $F_{i0}, F_{sdc}, F_{adc}, P_c, r_0, b_0, m+1$

Clock generation for the pulse profiling mode

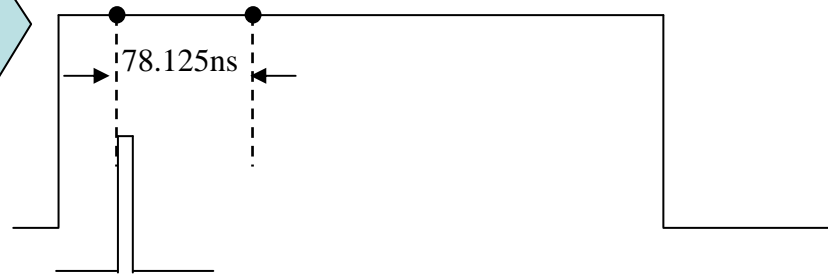


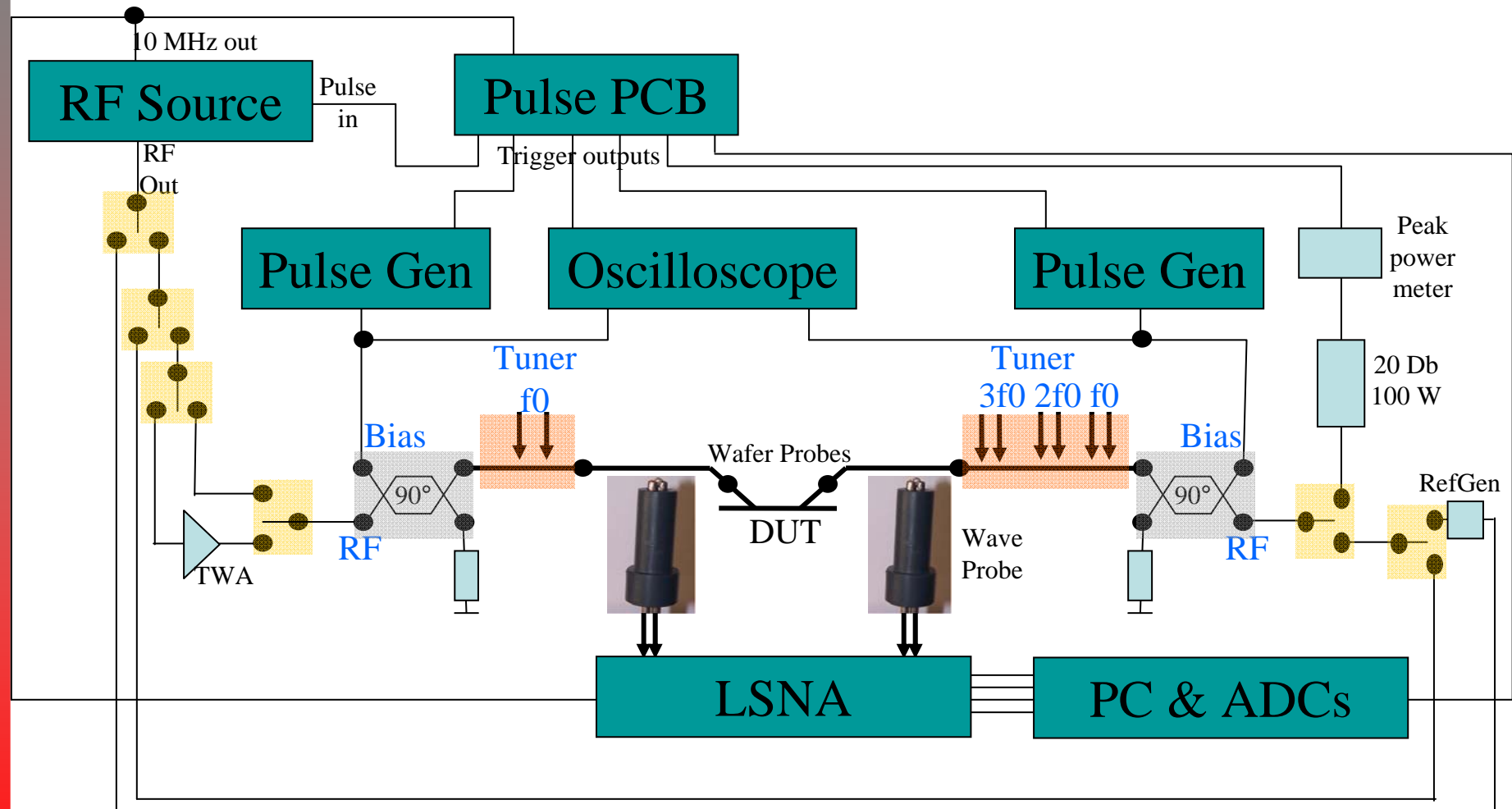
Pulse Profiling Parameters

Adjustable Trigger Delay for Pulse Profiling



Only 2 RF samples are taken (trade-off)





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V_{gs0} , V_{ds0} : bias point
 V_{gsi} , V_{dsi} : a pulsed point

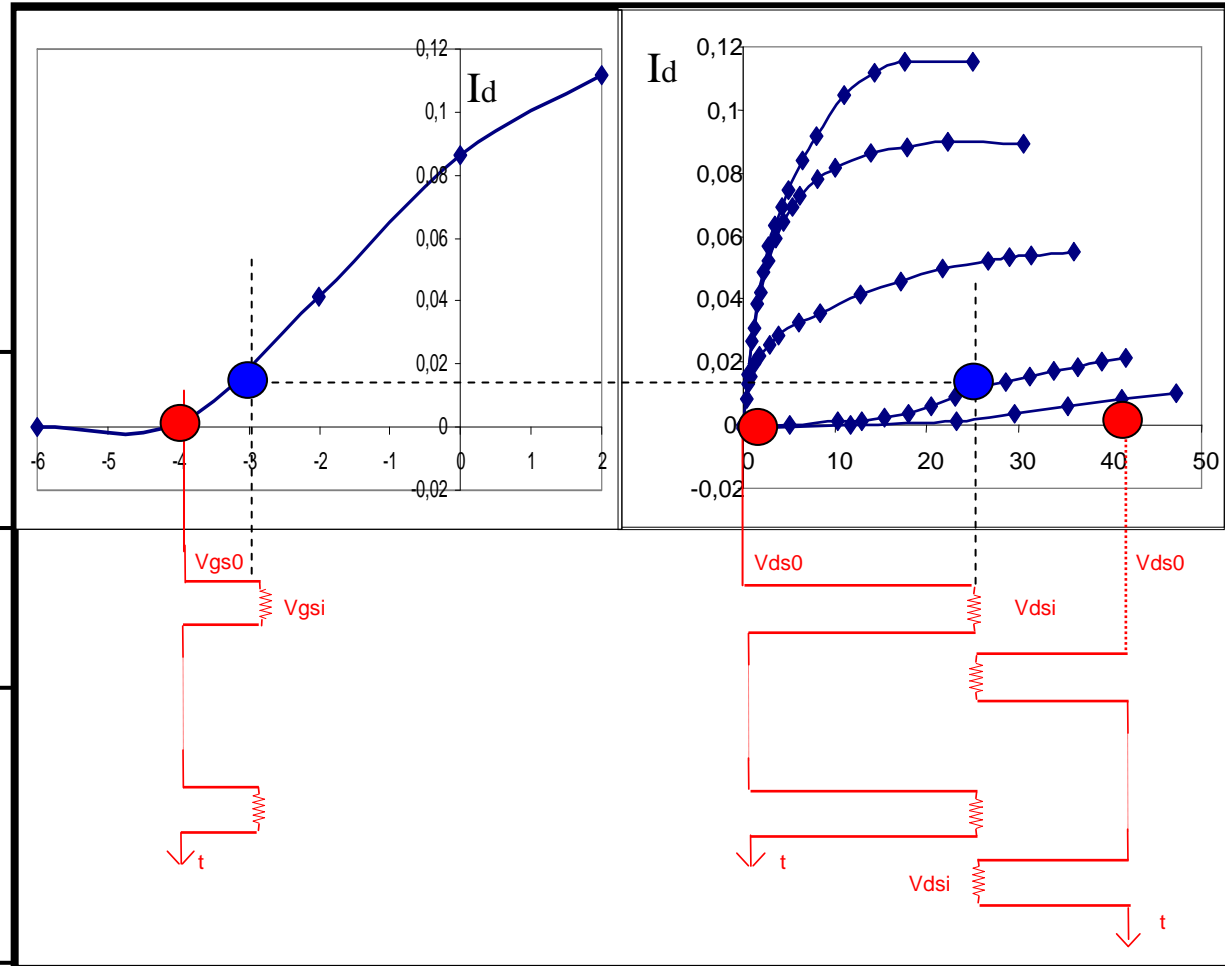
For our Measurements:

$V_{ds0} = 0V / 40V$
 $V_{gs0} = -4.5V = V_p$

$V_{dsi} = 25V$
 $V_{gsi} = -3V$

$P_{period} = 100 \mu s$

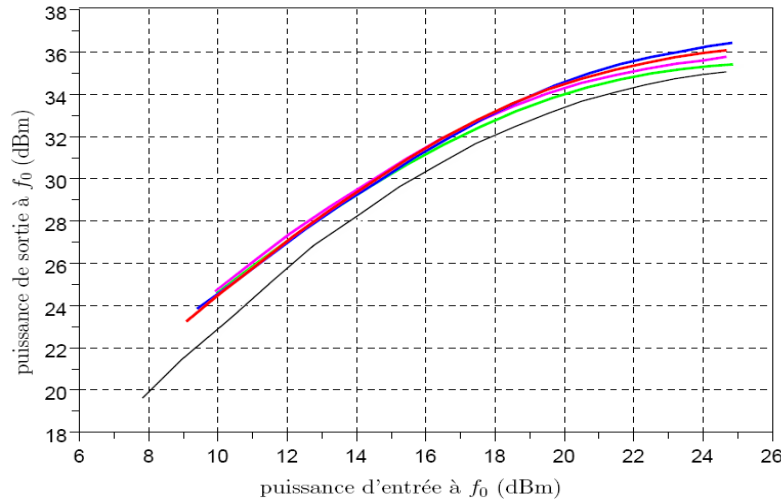
$P_{width} = 10 \mu s$



The PIV controls the thermal and traps history

Traps effects versus DC Bias point

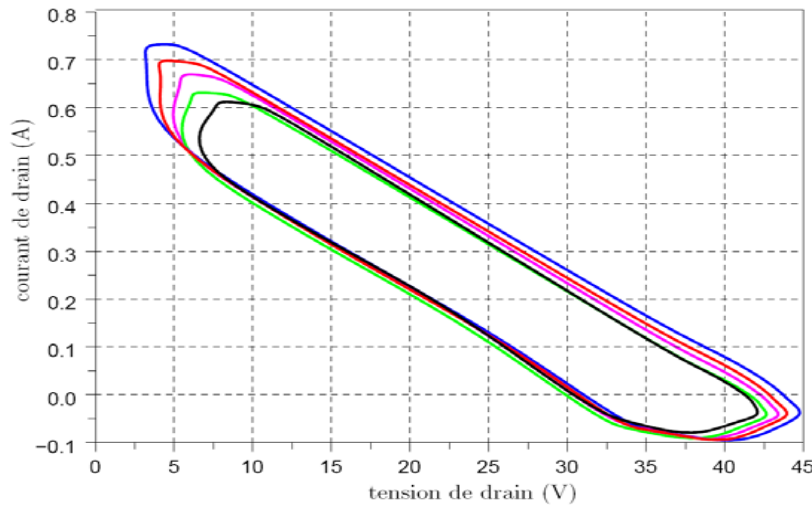
Output Power @f₀ for different polarizations of drain (0-10-25-40V) with fixed gain compression (2dB)



V_{dsi} = 25V for all the case

AB Polarization class

- █ CW
- █ Pulsed 10μs-100μs V_{ds0} @ 0V
- █ Pulsed 10μs-100μs V_{ds0} @ 10V
- █ Pulsed 10μs-100μs V_{ds0} @ 25V
- █ Pulsed 10μs-100μs V_{ds0} @ 40V



Cycles @f₀ with one input power for different Pulse biasing configuration with a fixed gain compression (2dB) and fixed delay.



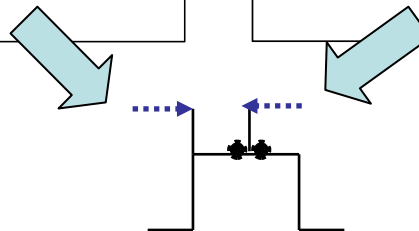
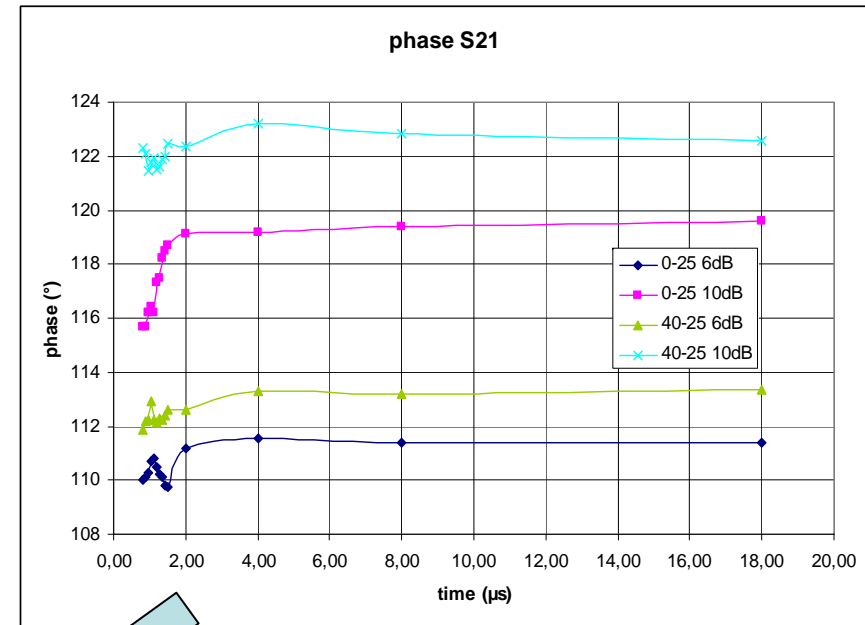
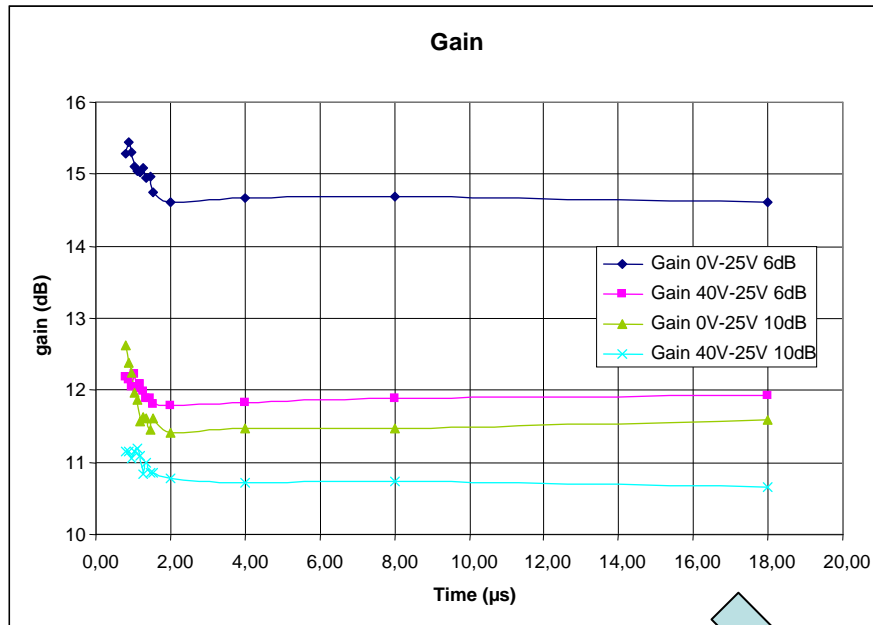
Pulse Profiling of Gain and Phase

Gain and Phase @f0 for different PIV configuration

V_{dsi}=25V; V_{ds0}=0V / 40V

For 2 Input Power Levels and Gain Compression of 6dB and 10 dB

AlGaN/GaN HEMT from Alcatel-thales III-V Lab, 1 mm gate width
V_{gs0}=-4.5=V_p; V_{gsi}=-3V



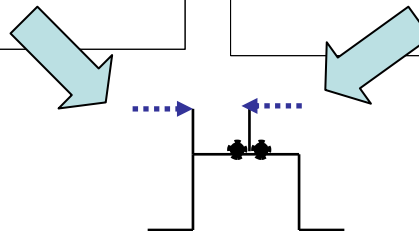
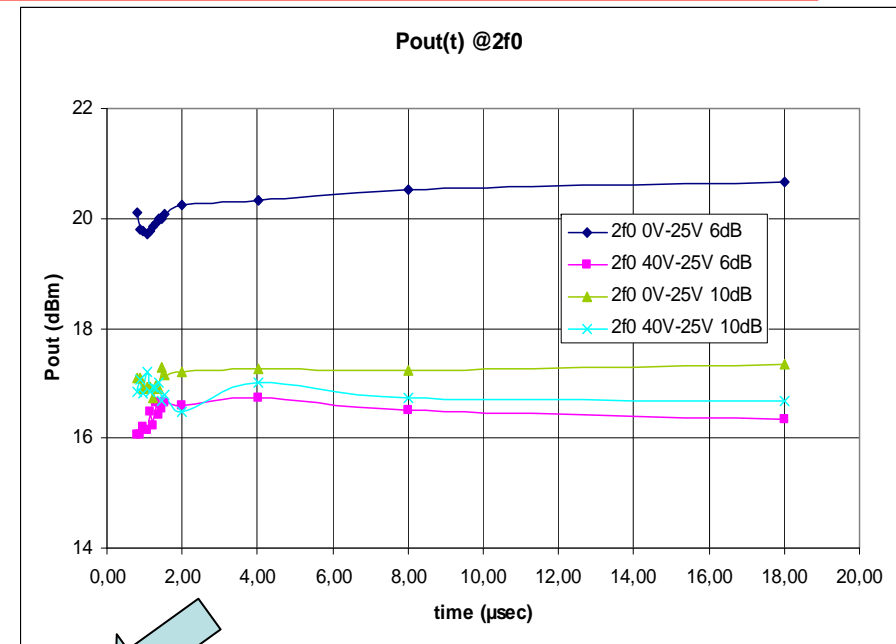
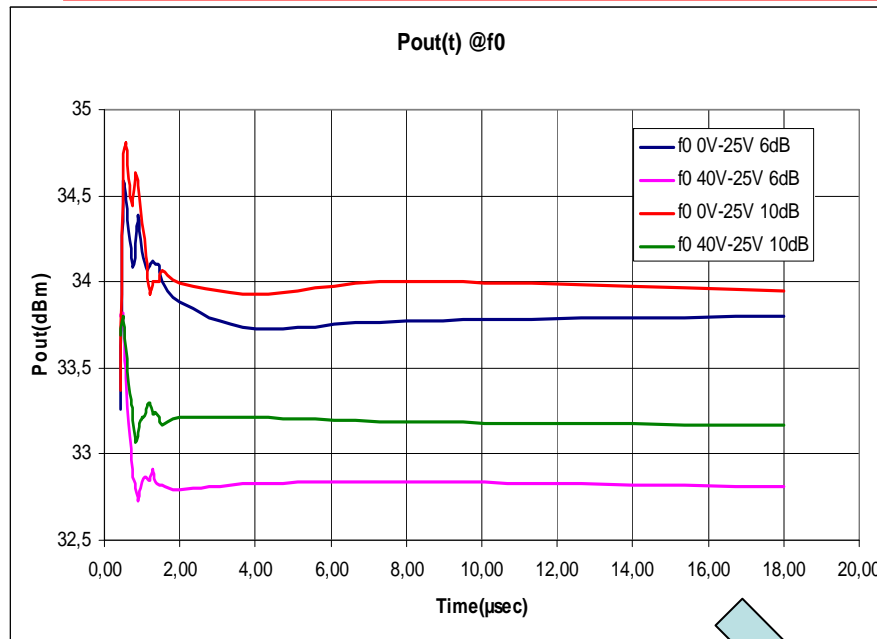
Output Power @f0 and @2f0 for different PIV configuration

V_{dsi}=25V; V_{ds0}=0V / 40V

For 2 Input Power Levels and Gain Compression of 6dB and 10 dB

AlGaIn/GaN HEMT from Alcatel-thales III-V Lab, 1 mm gate width

V_{gs0}=-4.5=V_p; V_{gsi}=-3V



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Conclusion

- New capabilities for the characterization of nonlinear microwave active circuits.
- Helpful for memory investigations within devices
- View of system-level consequences of memory effects

Future Works

- This work will allow us to perform Pulse to Pulse or Bursts of Pulses Characterizations.

Thank you for your attention